

MOS FIELD EFFECT TRANSISTOR

μ PA1757

SWITCHING N-CHANNEL POWER MOS FET INDUSTRIAL USE

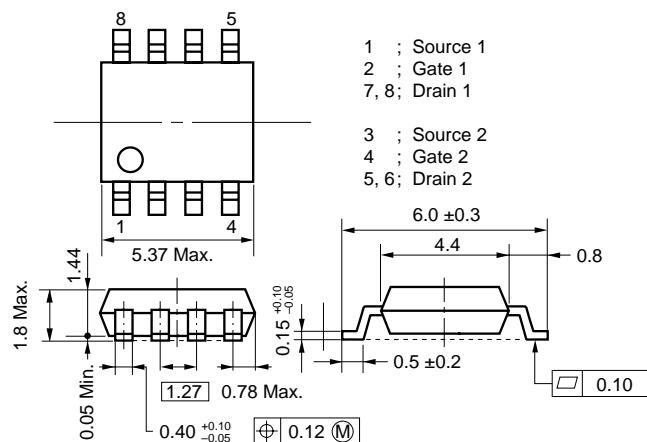
Description

This product is Dual N-Channel MOS Field Effect Transistor designed for power management application of notebook computers, and Li-ion battery application.

Features

- Dual MOS FET chips in small package
- 2.5 V gate drive type and low on-resistance
 $R_{DS(on)1} = 23 \text{ m}\Omega$ (MAX.) ($V_{GS} = 4.5 \text{ V}$, $I_D = 3.5 \text{ A}$)
 $R_{DS(on)2} = 32 \text{ m}\Omega$ (MAX.) ($V_{GS} = 2.5 \text{ V}$, $I_D = 3.5 \text{ A}$)
- Low C_{iss} $C_{iss} = 750 \text{ pF}$ Typ.
- Built-in G-S protection diode
- Small and surface mount package
(Power SOP8)

Package Drawing (Unit : mm)



Ordering information

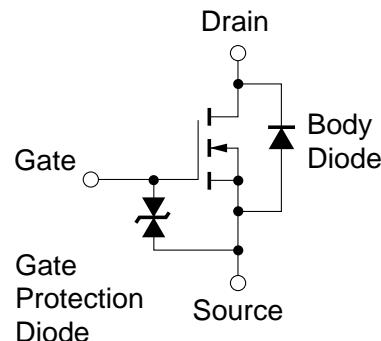
Part Number	Package
μ PA1757G	Power SOP8

Absolute Maximum Ratings ($T_A = 25^\circ\text{C}$)

Drain to source voltage	V_{DSS}	20	V
Gate to source voltage	V_{GSS}	± 12.0	V
Drain current (DC)	$I_{D(DC)}$	± 7.0	A
Drain current (pulse) ^{Note1}	$I_{D(pulse)}$	± 28	A
Total power dissipation (1 unit) ^{Note2}	P_T	1.7	W
Total power dissipation (2 unit) ^{Note2}	P_T	2.0	W
Channel temperature	T_{ch}	150	$^\circ\text{C}$
Storage temperature	T_{stg}	-55 to +150	$^\circ\text{C}$

Notes 1. PW $\leq 10 \mu\text{s}$, Duty Cycle $\leq 1\%$

2. $T_A = 25^\circ\text{C}$, Mounted on ceramic substrate of 2000 mm² x 1.1 mm



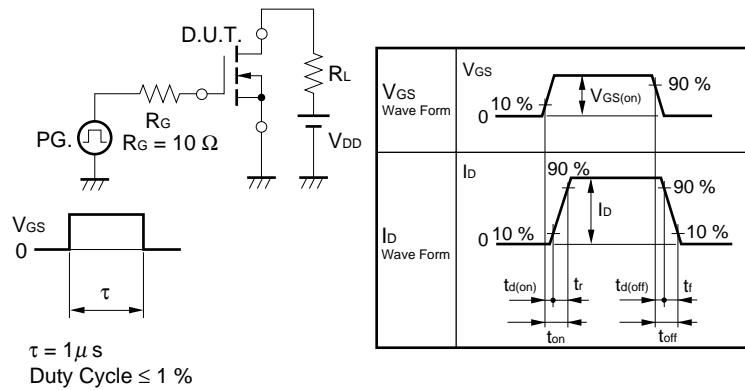
The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

The information in this document is subject to change without notice.

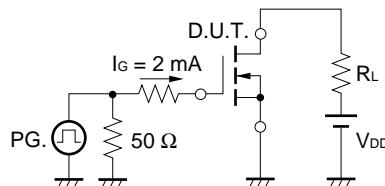
Electrical Characteristics ($T_A = 25^\circ C$)

Characteristics	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
Drain to source on-state resistance	$R_{DS(on)1}$	$V_{GS} = 4.5 V, I_D = 3.5 A$		16.2	23	$m\Omega$
	$R_{DS(on)2}$	$V_{GS} = 2.5 V, I_D = 3.5 A$		22	32	$m\Omega$
Gate to source cutoff voltage	$V_{GS(off)}$	$V_{DS} = 10 V, I_D = 1.0 mA$	0.5	0.8	1.5	V
Forward transfer admittance	$ y_{fs} $	$V_{DS} = 10 V, I_D = 3.5 A$	5.0	13		S
Drain leakage current	I_{DSS}	$V_{DS} = 20 V, V_{GS} = 0 V$			10	μA
Gate to source leakage current	I_{GSS}	$V_{GS} = \pm 12.0 V, V_{DS} = 0 V$			± 10	μA
Input capacitance	C_{iss}	$V_{DS} = 10 V$		750		pF
Output capacitance	C_{oss}	$V_{GS} = 0 V$		420		pF
	C_{rss}	$f = 1 MHz$		140		pF
Turn-on delay time	$t_{d(on)}$	$I_D = 3.5 A$ $V_{GS(on)} = 4.0 V$ $V_{DD} = 10 V$ $R_G = 10 \Omega$		57		ns
Rise time	t_r			206		ns
Turn-off delay time	$t_{d(off)}$			593		ns
Fall time	t_f			815		ns
Total gate charge	Q_G	$I_D = 7.0 A$ $V_{DD} = 16 V$ $V_{GS} = 4.0 V$		13.0		nC
Gate to source charge	Q_{GS}			2.6		nC
Gate to drain charge	Q_{GD}			5.3		nC
Body diode forward voltage	$V_{F(S-D)}$	$I_F = 7.0 A, V_{GS} = 0 V$		0.75		V

Test circuit 1 Switching time

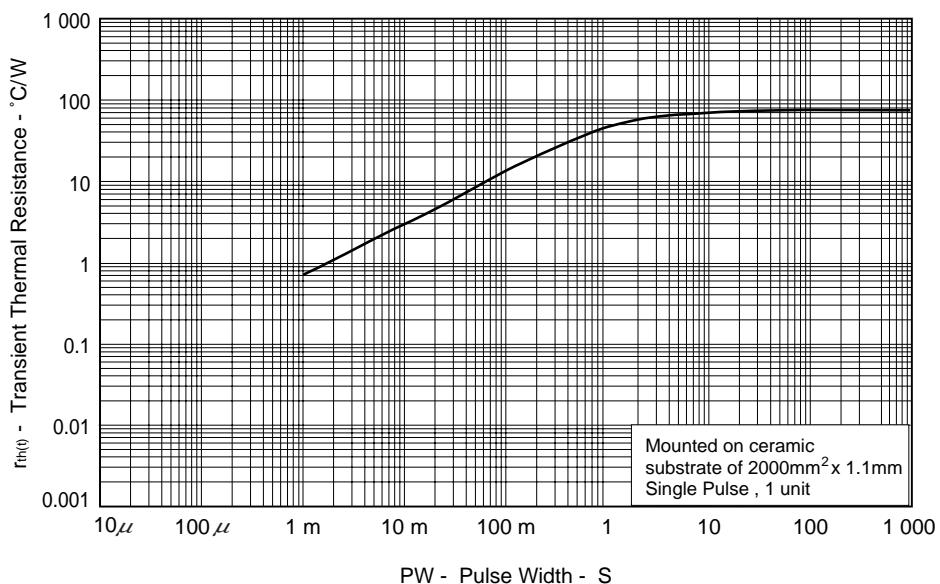


Test circuit 2 Gate charge

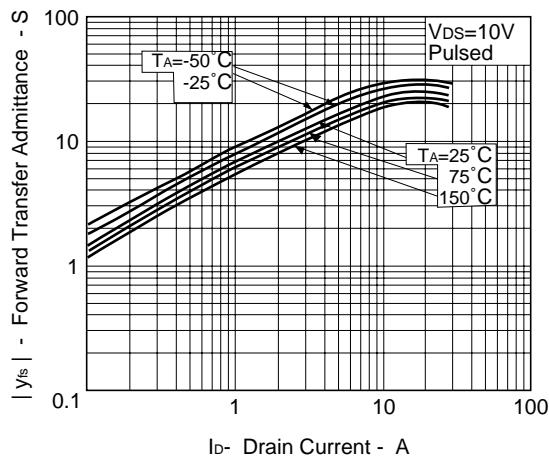


Typical Characteristics ($T_A = 25^\circ\text{C}$)

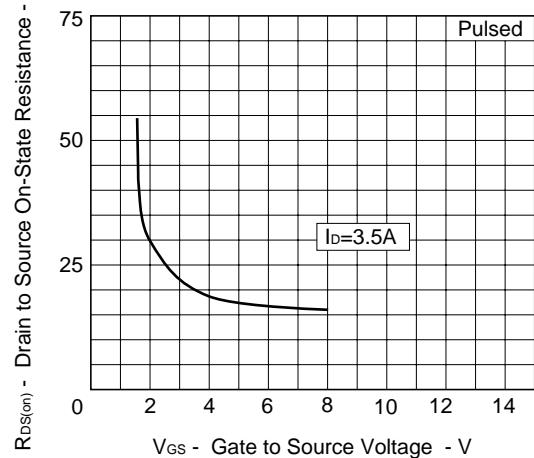
TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH



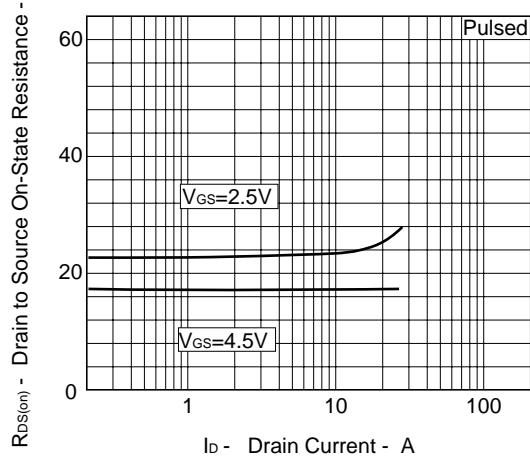
FORWARD TRANSFER ADMITTANCE vs. DRAIN CURRENT



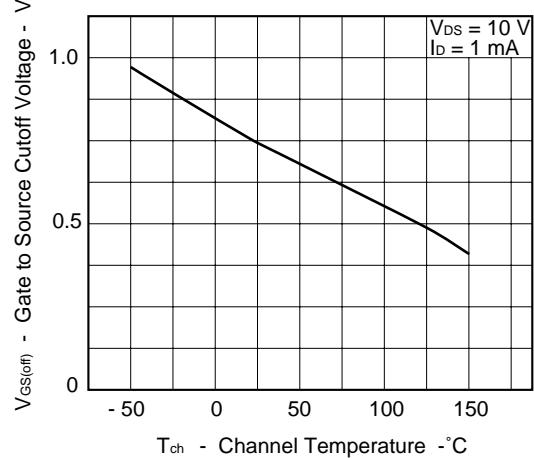
DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE

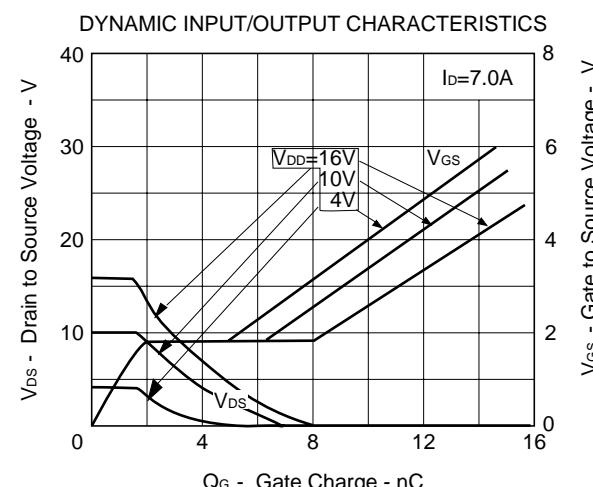
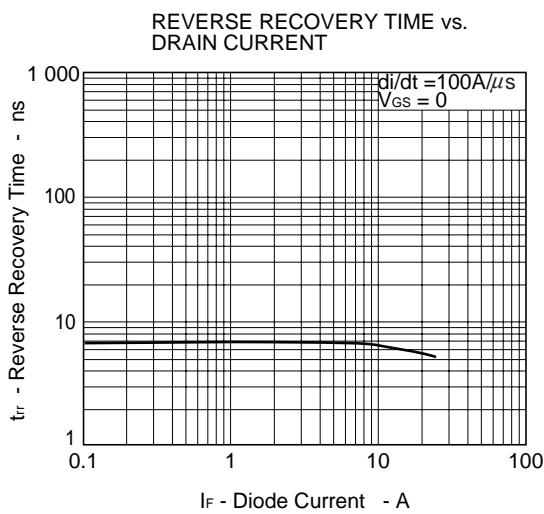
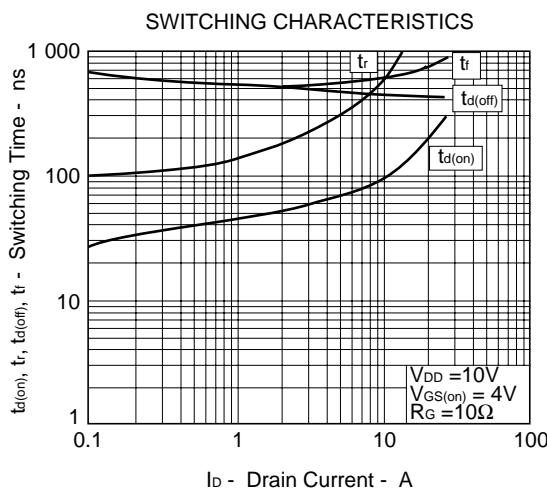
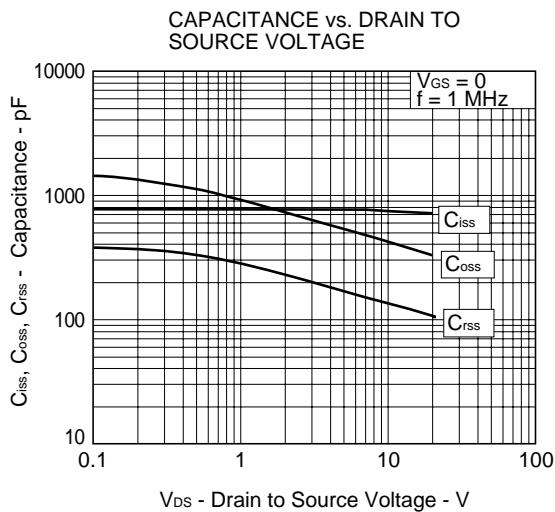
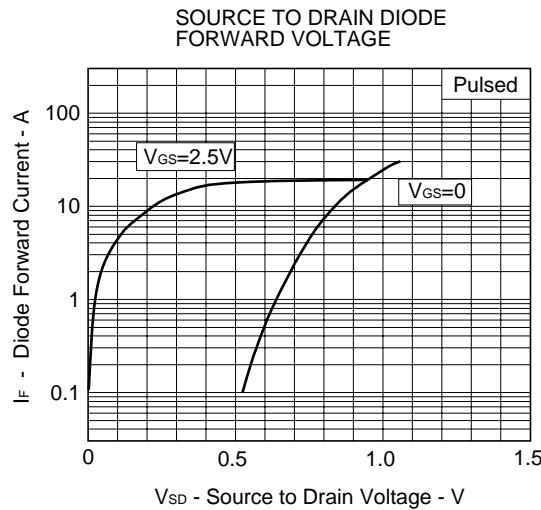
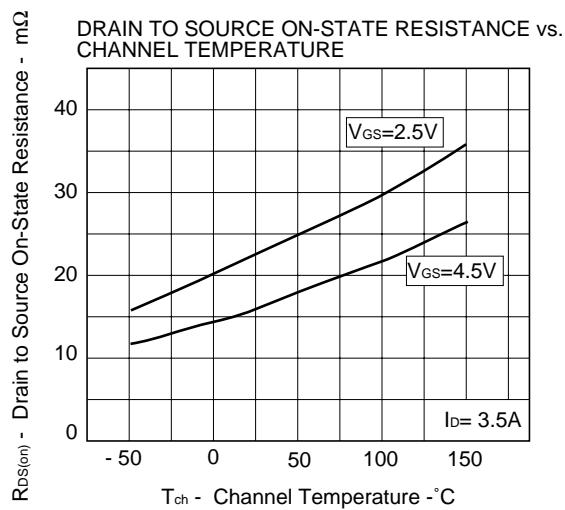


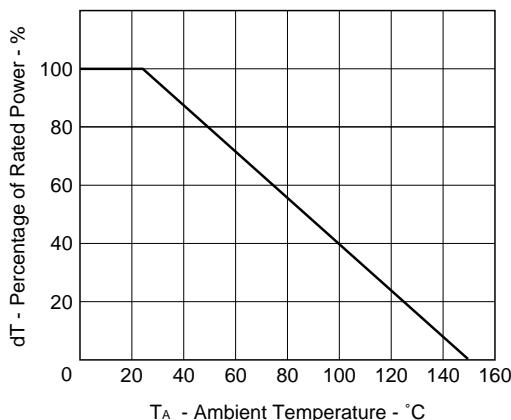
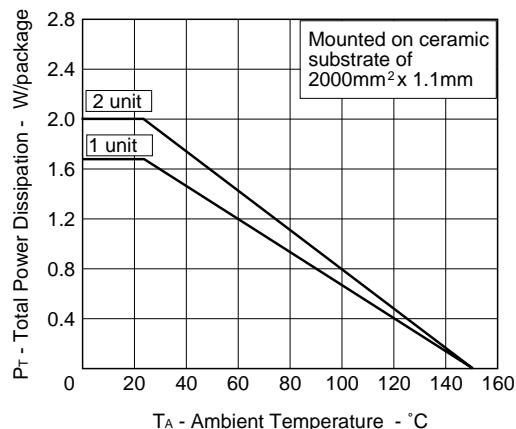
DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT



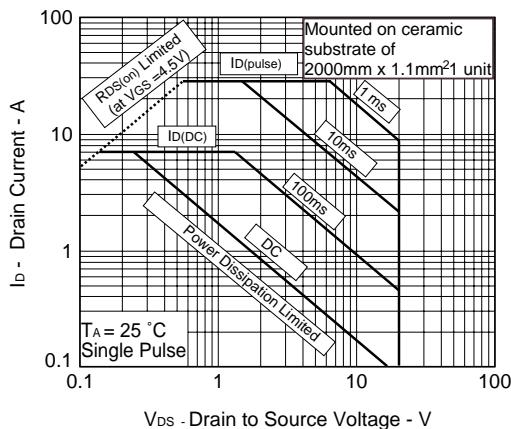
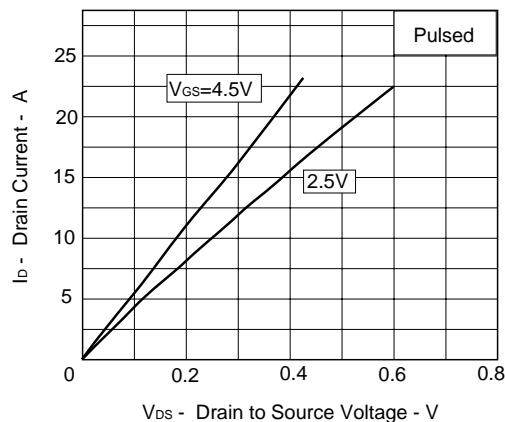
GATE TO SOURCE CUTOFF VOLTAGE vs. CHANNEL TEMPERATURE



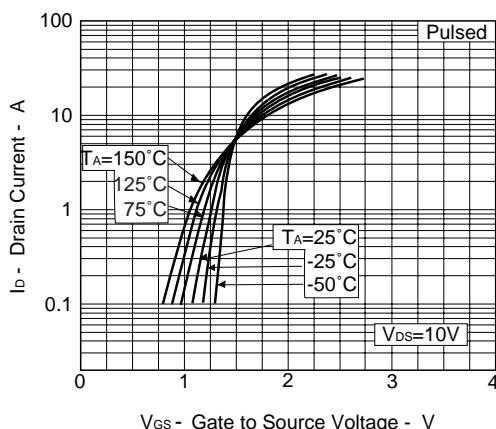


DERATING FACTOR OF FORWARD BIAS
SAFE OPERATING AREATOTAL POWER DISSIPATION vs.
AMBIENT TEMPERATURE

FORWARD BIAS SAFE OPERATING AREA

DRAIN CURRENT vs.
DRAIN TO SOURCE VOLTAGE

FORWARD TRANSFER CHARACTERISTICS



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[MEMO]

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Anti-radioactive design is not implemented in this product.



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